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July 2024

FDMS7700S

Dual N-Channel PowerTrench® MOSFET

N-Channel: 30 V, 30 A, 7.5 m Ω N-Channel: 30 V, 40 A, 2.4 m Ω

Features

Q1: N-Channel

- Max $r_{DS(on)}$ = 7.5 m Ω at V_{GS} = 10 V, I_D = 12 A
- Max $r_{DS(on)} = 12 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$, $I_D = 10 \text{ A}$

Q2: N-Channel

- Max $r_{DS(on)} = 2.4 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 20 \text{ A}$
- \blacksquare Max $\rm r_{DS(on)}$ = 2.9 m Ω at $\rm V_{GS}$ = 4.5 V, $\rm I_D$ = 18 A
- RoHS Compliant

General Description

This device includes two specialized N-Channel MOSFETs in a dual MLP package. The switch node has been internally connected to enable easy placement and routing of synchronous buck converters. The control MOSFF (was and synchronous SyncFETTM (Q2) have been designated prov. optimal power efficiency.

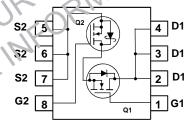
Applications

- Computing
- Commun. ation
- GE YE Se Point of LCA!
- teb k VCORF









l'ower :

SI T. 'aximumi Ratings TA = 25 °C ur lens otherwise noted

`ymb′	Far ameter	Q1	Q2	Units
V _{DS}	Drain to Source Voltage	30	30	V
V_{GS}	Cate to Source Voltag : (Note 3)	±20	±20	V
	Drain Current - Continuous T _C = 25 °C	30	40	
₽ \	-Continuous T _A = 25 °C	12 ^{1a}	22 ^{1b}	Α
	-Pulsed	40	60	1
P_{D}	Power Dissipation for Single Operation $T_A = 25 ^{\circ}\text{C}$	2.2 ^{1a}	2.5 ^{1b}	W
' D	T _A = 25 °C	1.0 ^{1c}	1.0 ^{1d}	, vv
T_J , T_{STG}	Operating and Storage Junction Temperature Range	-55 to	+150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	57 ^{1a}	50 ^{1b}	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	125 ^{1c}	120 ^{1d}	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	3.5	2	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS7700S	FDMS7700S	Power 56	13 "	12 mm	3000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units
Off Chara	octeristics						
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$ $I_D = 1 \text{ mA}, V_{GS} = 0 V$	Q1 Q2	30 30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C I_D = 1 mA, referenced to 25 °C	Q1 Q2		15 14		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V	Q1 Q2			1 500	μA μA
I _{GSS}	Gate to Source Leakage Current	V _{GS} = 20 V, V _{DS} = 0 V	Q1 Q2			100 100	nA nA

On Characteristics

		1		-		
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$ $V_{GS} = V_{DS}, I_D = 1 mA$	Q1 1 Q2 1	1.8	3 3	15
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25 °C $I_D = 1 \text{ mA}$, referenced to 25 °C	Q2	-4	10	nıV/°C
r _{DS(on)}	Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 12 \text{ A}$ $V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 1^2 \text{ A}, T_J$ $V_{GS} = 10 \text{ V}, I_D = 1^2 \text{ A}, T_J$ $V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$ $V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$	2 020	6.0 8.3 5.3 1.9 2.4	7.5 12 12 2.4 2.9 3.4	mΩ
g _{FS}	Forward Transconductance	$V_{DS} = 5$ $I_{D} = 1_{2}$ $S_{S} = 5 \text{ V}, S_{S} = 20 \text{ A}$	Q1 Q2	63 150	10	S
Dynamic	: Characteristics	S ENV	Rai	Mr		

Dynamic Characteristics

C	Input Capacitance Q1:	Ω1),	1315	1750	pF
C _{iss}	$V_{DS} = 15 \text{ V} \text{ V}_{GS} = 0 \text{ V, f} = 1 \text{ MHZ}$	C2		7240	9630	PΓ
C _{oss}	Output Capa ance	Q1		445	600	pF
Ooss	Q2;	Q2		2690	3580	рі
C	Re Tran r Cap itance $V_{DS} = 15 \text{ V } V_{CS} = 0 \text{ V, } r = 1 \text{ MHZ}$	Q1		45	70	pF
C _{rss}	ite 1 Ital. I Cap Italice	Q2		185	280	PΓ
D	Gau nesist ce	Q1		0.9		Ω
R_g	Odio Nesisi Ce	Q2		8.0		7.5

vitchi. C racteristics

t _{d(oi}	Turn On Delay Timo			Q1 Q2	8.6 21	18 34	ns
t _r	Rise Time	Q1: V _{DD} = 15 V, I _D = 12	A, $R_{GEN} = 6 \Omega$	Q1 Q2	2.5 9.2	10 18	ns
t _{a(off)}	Turn-Off Delay 7in.	Q2:	A P	Q1 Q2	20 58	32 93	ns
i _f	Fall Time	$V_{DD} = 15 \text{ V}, I_{D} = 20 \text{ A}, R_{GEN} = 6 \Omega$	Q1 Q2	2.3 6.8	10 14	ns	
Q_g	Total Gate Charge	V _{GS} = 0 V to 10 V	· ·	Q1 Q2	20 105	28 147	nC
Q _g	Total Gate Charge	V _{GS} = 0 V to 4.5 V	V _{DD} = 15 V, I _D = 12 A	Q1 Q2	9.3 48	13 67	nC
Q _{gs}	Gate to Source Gate Charge		Q2 V _{DD} = 15 V,	Q1 Q2	4.3 19		nC
Q_{gd}	Gate to Drain "Miller" Charge		$I_D = 20 \text{ A}$	Q1 Q2	2.2 11		nC

Electrical Characteristics T_J = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units	
Drain-Source Diode Characteristics								
V _{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 12 \text{ A}$ (Note 2) $V_{GS} = 0 \text{ V}, I_S = 20 \text{ A}$ (Note 2)	Q1 Q2		0.8 0.7	1.2 1.2	V	
t _{rr}	Reverse Recovery Time	Q1 I _F = 12 A, di/dt = 100 A/μs	Q1 Q2		27 53	43 85	ns	
Q _{rr}	Reverse Recovery Charge	Q2 $I_F = 20 \text{ A, di/dt} = 300 \text{ A/}\mu\text{s}$	Q1 Q2		10 100	18 160	nC	

Notes

1: R_{DJA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{DJC} is guaranteed by design while R_{DCA} is determined by the user's board design.



a. 57 °C/W when mounted on a 1 in² pad of 2 oz copper



b. 50 °C/W when m ted on a 1 in² r i 2 o. ppper



c. 125 °C/W when mounted on minimum pad of 2 oz copper



1. 120 °C/W' wheremounted on a minimum, pind of 2 oz copise.

- 2: Pulse Test: Pulse dth < 2000, Du. < 2.0%

Typical Characteristics (Q1 N-Channel)T_J = 25°C unless otherwise noted

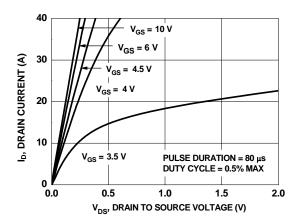


Figure 1. On Region Characteristics

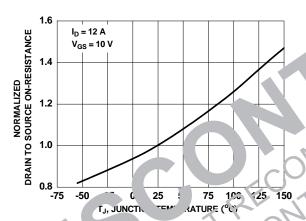


Figure 3. Norm ized On Registance vs im non Temperature

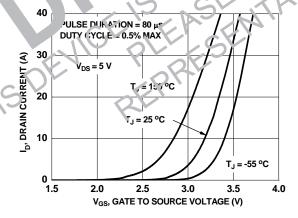


Figure 5. Transfer Characteristics

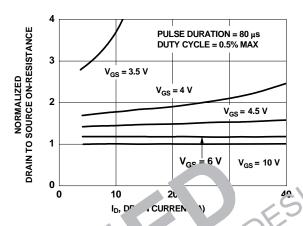


Figure 2. 1 rm. 3d On-Resistance vs Prain (rrei ar 3ate Voitage

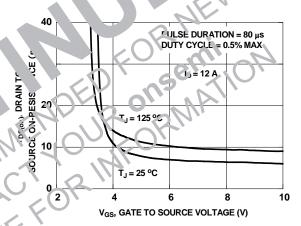


Figure 4. On-Resistance vs Gate to Source Voltage

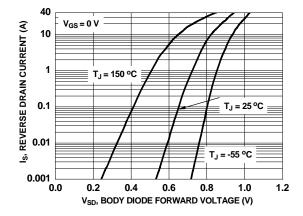


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q1 N-Channel)T_J = 25°C unless otherwise noted

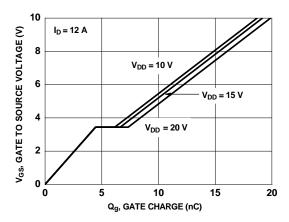


Figure 7. Gate Charge Characteristics

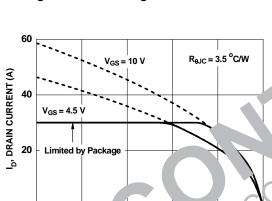


Fig. 165. Likin in Continuous Drain urrent v. Case Temperature

75

00

. C, CAL "EMPF TURE (°C)

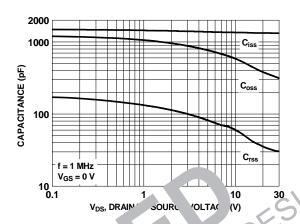


Figure 8. Tap ince vs prain to Sou to V age

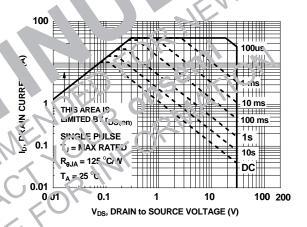


Figure 10. Forward Bias Safe Operating Area

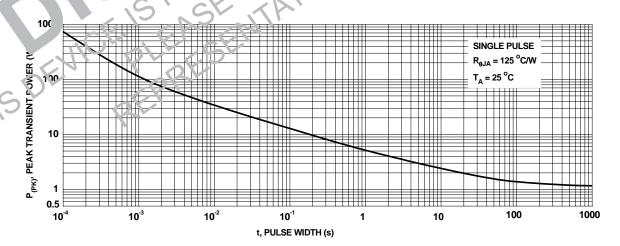


Figure 11. Single Pulse Maximum Power Dissipation

25



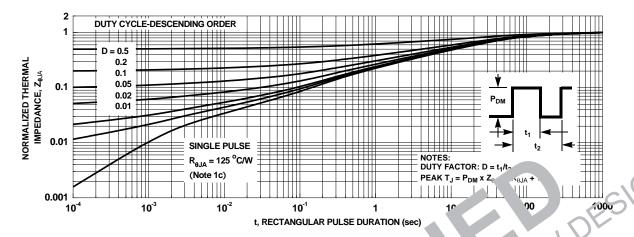


Figure 12. Junction-to-Ambient Transient Thermal Res. ans. Sur

Typical Characteristics (Q2 SyncFET)

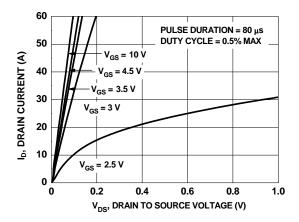


Figure 13. On-Region Characteristics

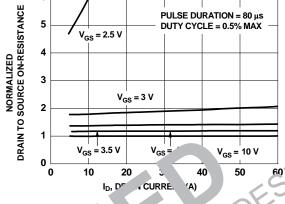
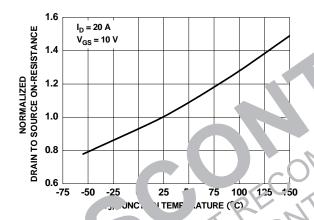


Figure 14. No hall. on-Resistance va Drain Curro har. Get Voltage



F. (re ... No) alized On-1 esistance vs 'ur ...on Temperature

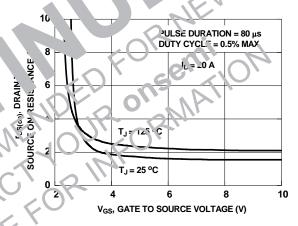


Figure 16. On-Resistance vs Gate to Source Voltage

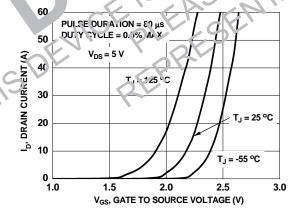


Figure 17. Transfer Characteristics

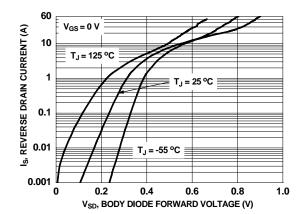


Figure 18. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q2 SyncFET)

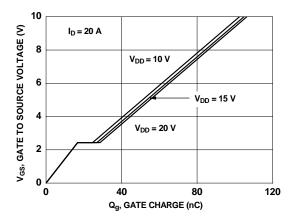


Figure 19. Gate Charge Characteristics

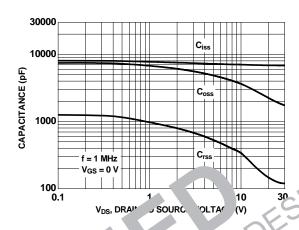
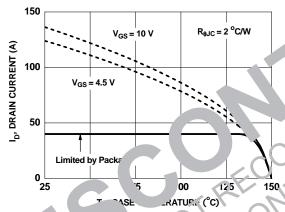


Figure 1. C _citance vs Drain tc \ \ \con_2 \ \ \cage



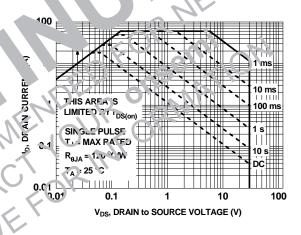


Figure 22. Forward Bias Safe Operating Area

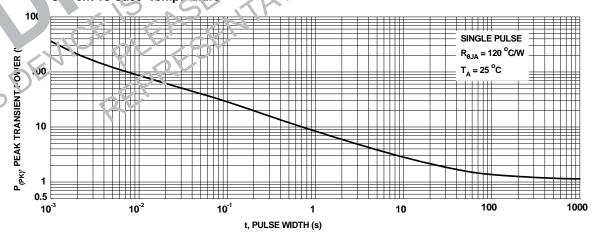


Figure 23. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q2 SyncFET)

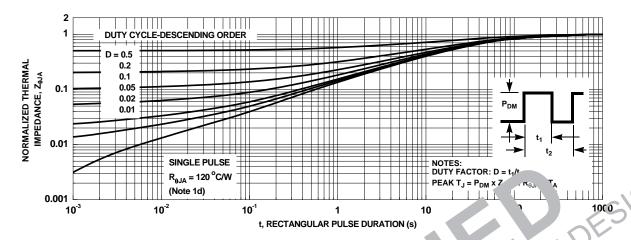


Figure 24. Junction-to-Ambient Transient Thermal specific ve

Typical Characteristics (continued)

SyncFETTM Schottky Body Diode Characteristics

Fairchild's SyncFETTM process embeds a Schottky diode in parallel with PowerTrench[®] MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 25 shows the reverse recovery characteristic of the FDMS7700S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

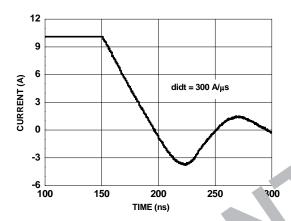


Figure 25. FDMS7700S F ACFL TM L dy

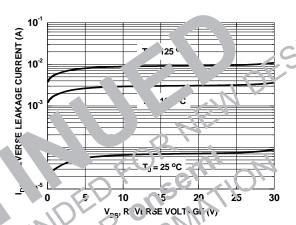
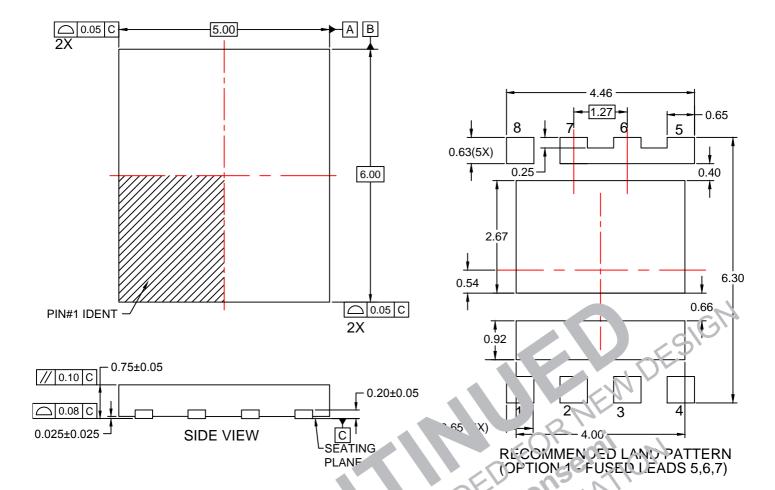
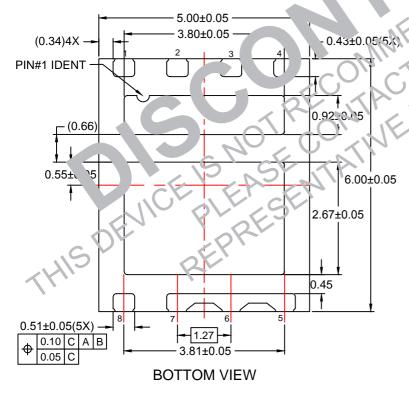


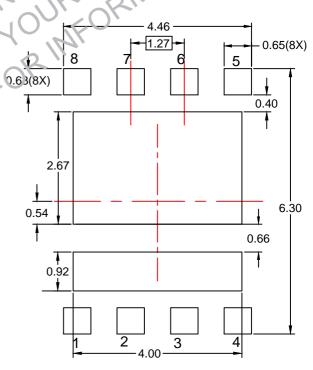
Figure 26. Syncl ETTM Body Diode Reverse Leakage vs. Prain-Source Voltage





NOTES:

- A. PACKAGE DOES NOT FULLY CONFORM TO JEDEC STANDARD.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. LAND PATTERN RECOMMENDATION IS EXISTING INDUSTRY LAND PATTERN.
- E. DRAWING FILENAME: MKT-MLP08Prev2.



RECOMMENDED LAND PATTERN (OPTION 2 - ISOLATED LEADS)





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